

Radiation hardness in Si detectors

Tuesday 12 July 2016 14:05 (1 hour)

Radiation hardness in semiconductor detectors. 3D detectors.

Author: PELLEGRINI, Giulio (Centro Nacional de Microelectrónica (IMB-CNM-CSIC) (ES))

Presenter: PELLEGRINI, Giulio (Centro Nacional de Microelectrónica (IMB-CNM-CSIC) (ES))

Session Classification: X-ray and charged particle detectors